

Effects of NH_4SCN additive in the FAPbI_3 perovskite films in a sequential deposition method

Table S1. Elemental analysis by energy-dispersive X-ray on bar-shaped morphology in 20% film.

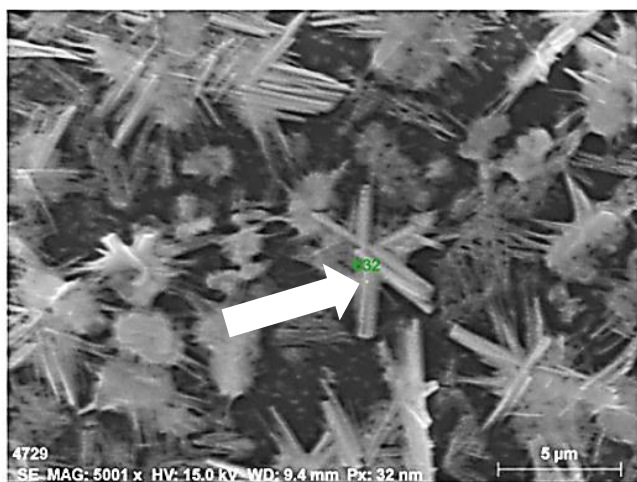
| Element | Weight % | Atomic % | Error % |
|---------|----------|----------|---------|
| Pb M | 43.20 | 22.16 | 2.55 |
| I L | 26.31 | 22.04 | 1.87 |
| Si K | 6.12 | 23.18 | 0.61 |
| S K | 0.04 | 0.14 | 0.06 |
| C K | 0.03 | 0.27 | 0.17 |
| N K | 0.00 | 0.00 | 0.00 |

Table S2. Elemental Analysis by energy-dispersive X-ray of p-40% film after first annealing.

| Element | Weight % | Atomic % | Error % |
|---------|----------|----------|---------|
| Pb M | 40.16 | 22.16 | 2.55 |
| I L | 38.04 | 22.04 | 1.87 |
| Si K | 8.78 | 23.18 | 0.61 |
| S K | 1.19 | 0.14 | 0.06 |
| C K | 1.18 | 0.27 | 0.17 |
| N K | 0.69 | 0.00 | 0.00 |

Table S3. Elemental Analysis by energy-dispersive X-ray of 40% film after second annealing.

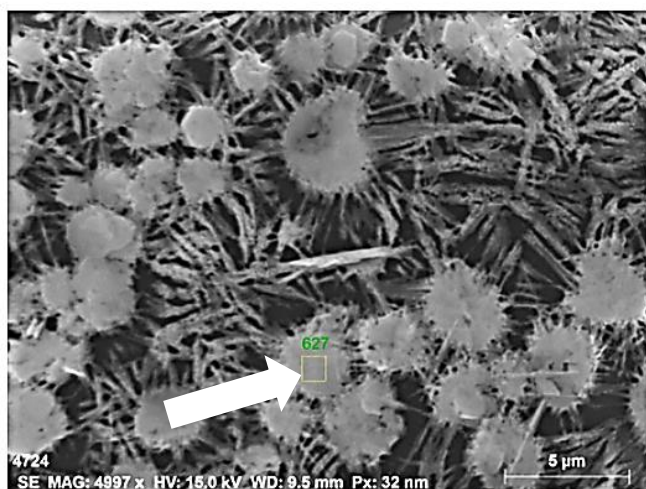
| Element | Weight % | Atomic % | Error % |
|---------|----------|----------|---------|
| Pb M | 28.29 | 7.25 | 1.47 |
| I L | 37.02 | 15.50 | 1.53 |
| Si K | 18.38 | 34.76 | 1.01 |
| S K | 0.01 | 0.01 | 0.03 |
| C K | 0.04 | 0.17 | 0.13 |
| N K | 2.68 | 10.18 | 1.33 |



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Table S4. Elemental Analysis by energy-dispersive X-ray of p-50% film over a precipitate.

| Element | Weight % | Atomic % | Error % |
|---------|----------|----------|---------|
| Pb M | 41.52 | 13.27 | 2.01 |
| I L | 34.54 | 18.02 | 1.63 |
| Si K | 9.44 | 22.26 | 0.64 |
| S K | 3.65 | 7.54 | 0.34 |
| C K | 1.72 | 9.46 | 1.03 |
| N K | 1.62 | 7.66 | 1.21 |



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Table S5. Elemental Analysis by energy-dispersive X-ray of p-50% films over a waffle morphology.

| Element | Weight % | Atomic % | Error % |
|---------|----------|----------|---------|
| Pb M | 37.60 | 16.86 | 1.21 |
| I L | 50.12 | 36.70 | 1.44 |
| Si K | 6.67 | 22.07 | 0.33 |
| S K | 0.00 | 0.00 | 0.00 |
| C K | 0.18 | 1.42 | 0.18 |
| N K | 0.00 | 0.00 | 0.00 |

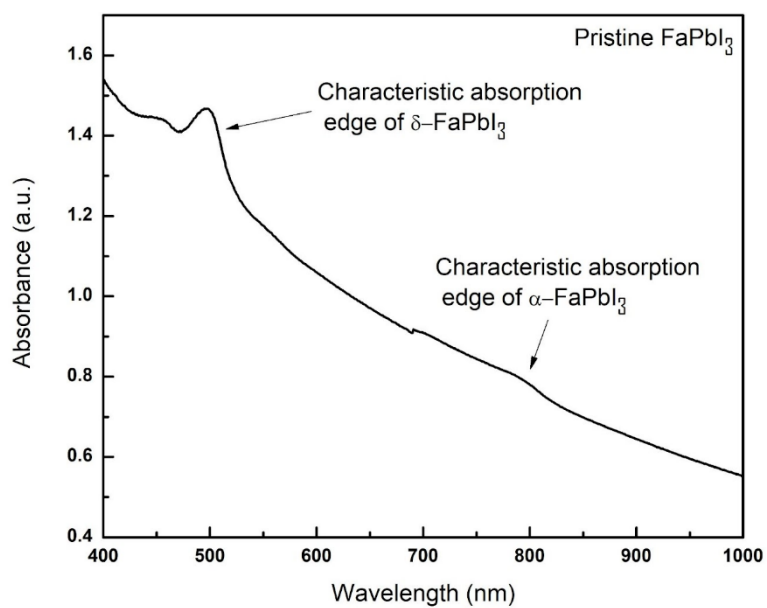


Figure S1. Absorbance spectrum of pristine FAPbI_3 (0% of NH_4SCN).

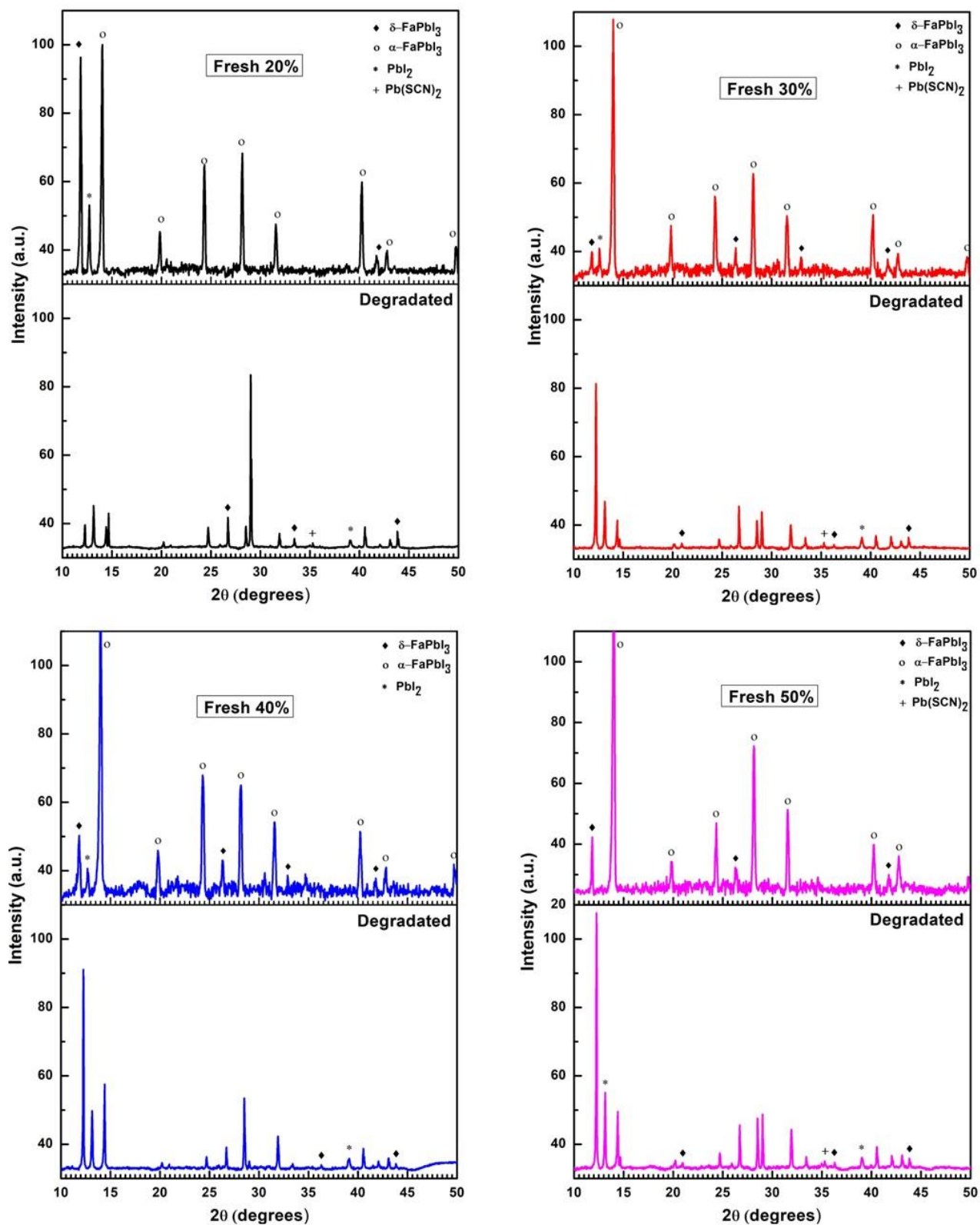


Figure S2. Comparative XRD patterns between fresh FAPbI₃ and degraded FAPbI₃ with different concentration of NH₄SCN.

Additional information of p-80% and 80% film

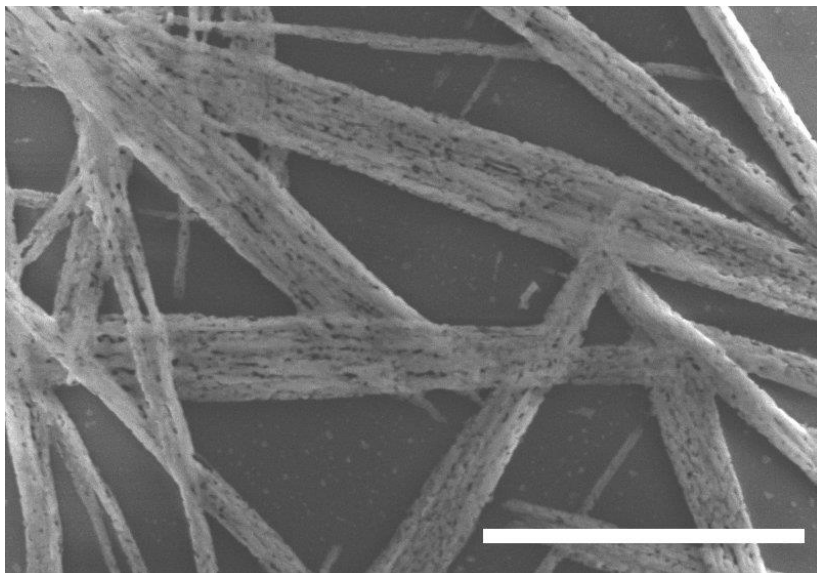


Figure S3. Top-view SEM micrograph of p-80% film. The white scale bar indicates 10 μm .

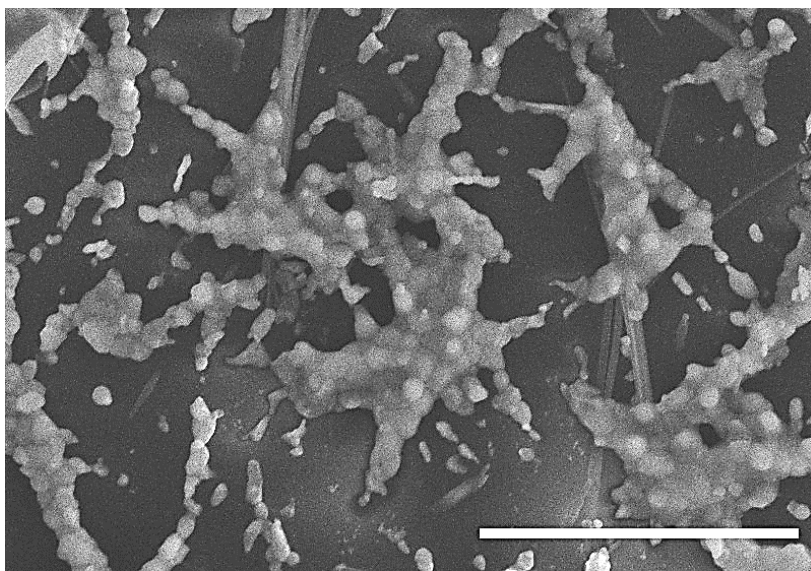


Figure S4. Top-view SEM micrograph of FAPbI₃ perovskite film with 80% concentration of NH₄SCN. White scale bar indicates 10 μm .

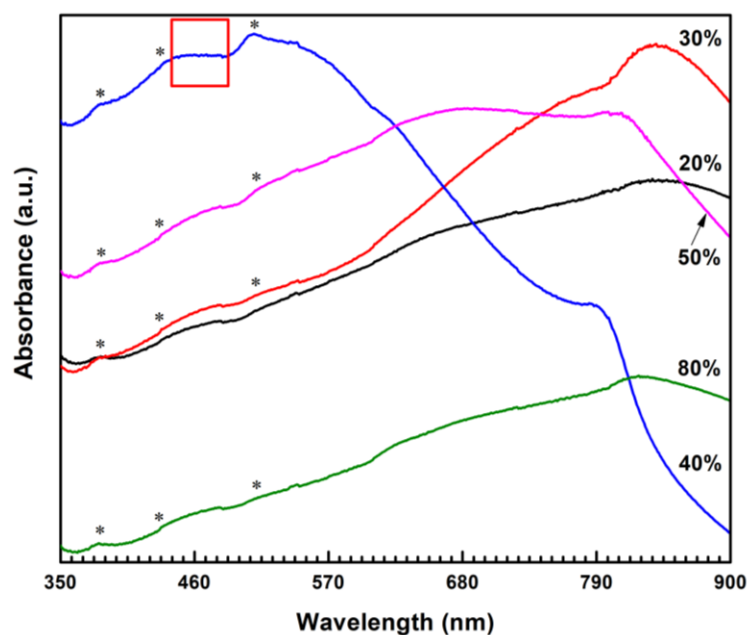


Figure S5. Absorbance UV-Vis light spectra of FAPbI₃ perovskite films with different concentration of NH₄SCN including 80%.

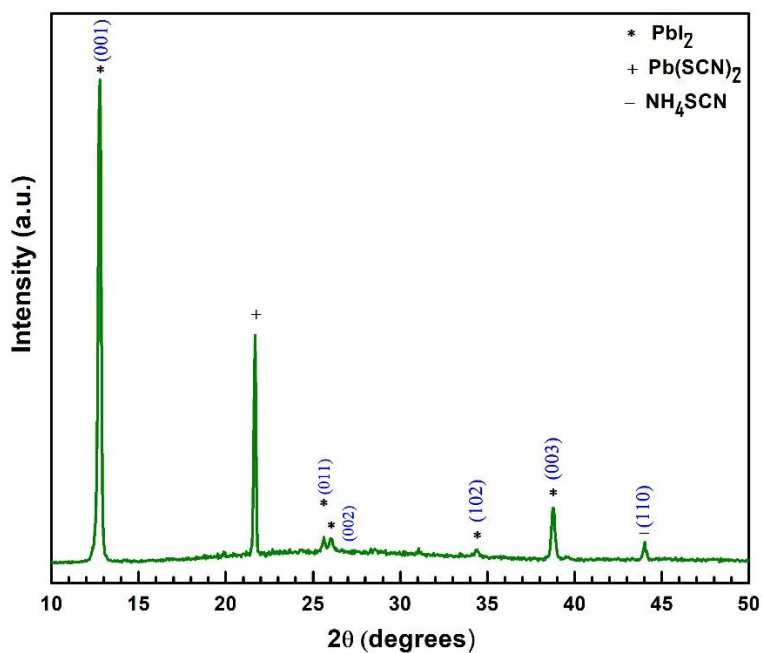


Figure S6. XRD patterns of the FAPbI₃ perovskite film with 80% concentration of NH₄SCN